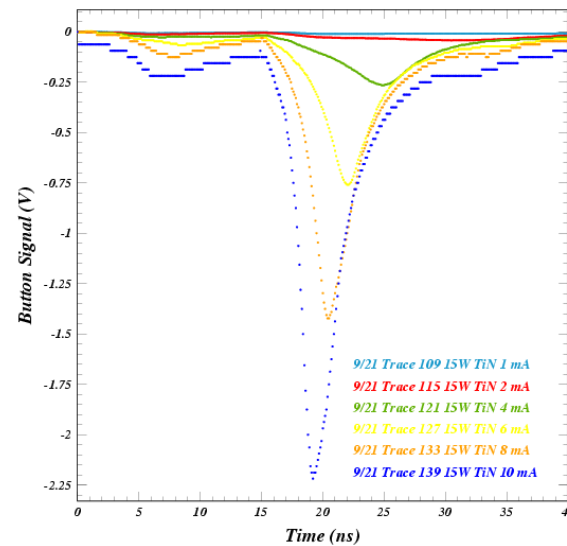
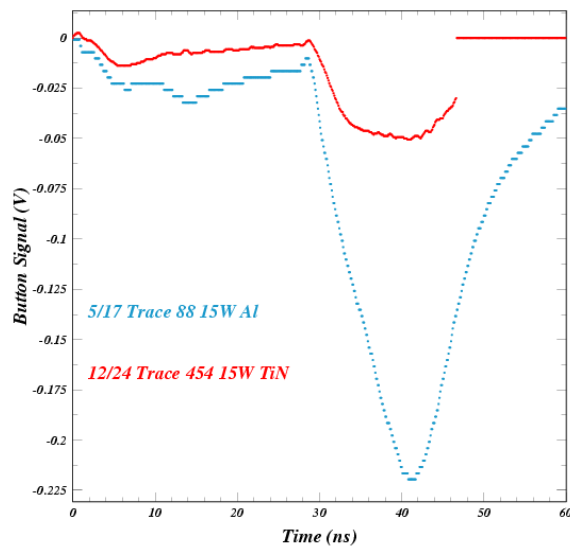




Comparison of Electronic Cloud Abatement Techniques Under Same Beam Conditions and Constraining Photoelectron Energy Distributions Using Bunch-Current Scans



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CesrTA Electron Cloud Meeting

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2010

Date	Species	(GeV)	Bunch Current (mA)	15E/W	Vacuum Chamber	Spacing	Data Sets	ECLLOUD
03/27/10	Positrons	5.3	5	W	Carbon (1)	14-84	11-74	19271-19306
				E	TiN		11-74	18404-18439
03/27/10	Electrons	5.3	5	W	Carbon (1)	14-70	110-146	
				E	TiN		110-146	
05/09/10	Positrons	2.1	3	W	Al	4-140	43-85	
				E	Carbon (2)		73-199	
05/09/10	Electrons	2.1	3	W	Al	4-20	91-103	
				E	Carbon (2)		217-253	
05/17/10	Positrons	5.3	3	W	Al	4-100	70-109	17781-17858
				E	Carbon (2)		139-211	19793-19870
05/17/10	Electrons	5.3	3	W	Al	4-100	166-199	
				E	Carbon (2)		325-391	
05/19/10	Electrons	2.1	3	W	Al	4-120	91-139	
				E	Carbon (2)		181-277	
12/24/10	Positrons	5.3	3,5	W	TiN	14-84	436-491	
				E	Carbon (2)		436-491	
12/24/10	Electrons	5.3	3,5	W	TiN	14-84	496-551	

The December data sets were designed to study the dependence of the witness bunch studies on bunch current. They provide an opportunity to address Mark's request for vacuum chamber comparisons for the same beam energy, species, bunch current and spacing, and reflected photon contribution (15E/W).

For TiN and Carbon we can increase the sample of comparisons at 2 GeV in the 2011 data-taking periods. We have not yet submitted the Task Overview sheets for these measurements.



15W

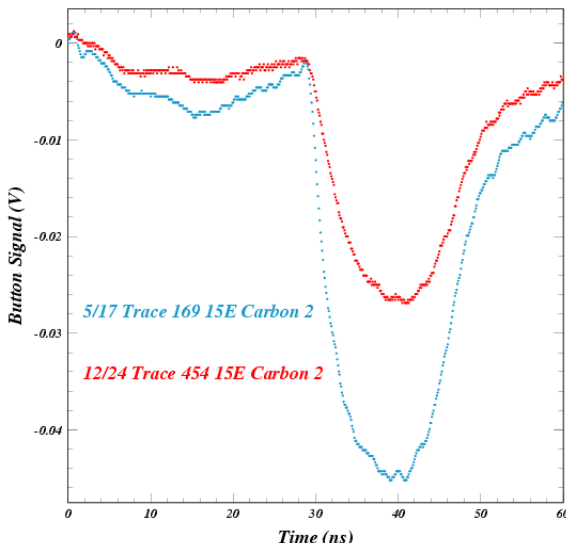
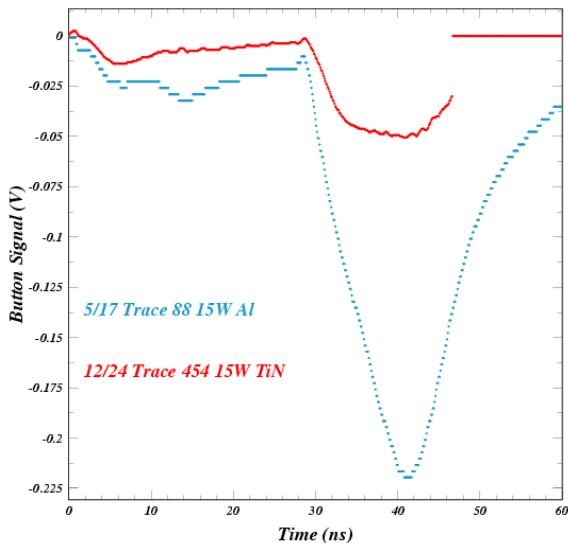
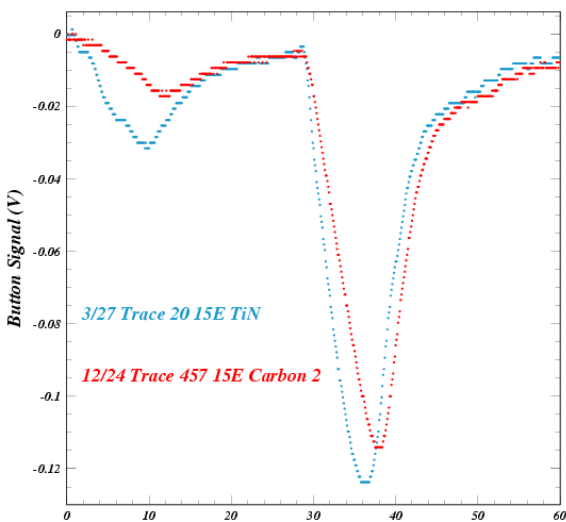
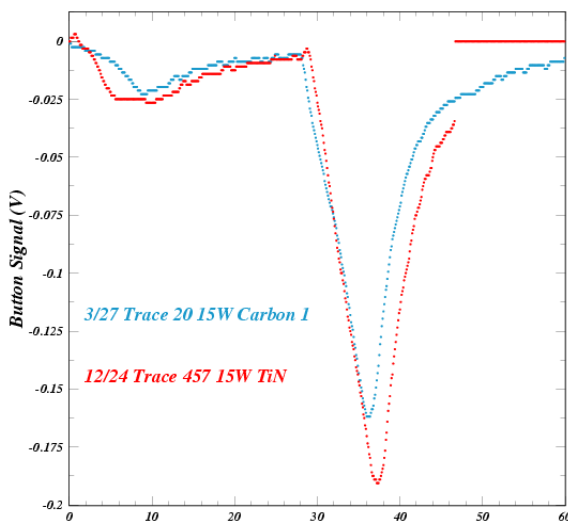
15E

5 mA/bunch

The results for the second carbon-coated chamber corroborate the high-energy photoelectron suppression relative to TiN observed with the first carbon chamber.

3 mA/bunch

The second carbon-coated chamber shows conditioning effects between 5/17 and 12/24, primarily for the quantum efficiency.



The carbon coating suppresses high-energy photoelectrons compared to the TiN coating.

The q.e. for reflected photons and the SEY are both much smaller for TiN compared to Al.

The 3-mA TiN witness signal is a factor of 5 smaller than for 5 mA/bunch. (see slide 5)

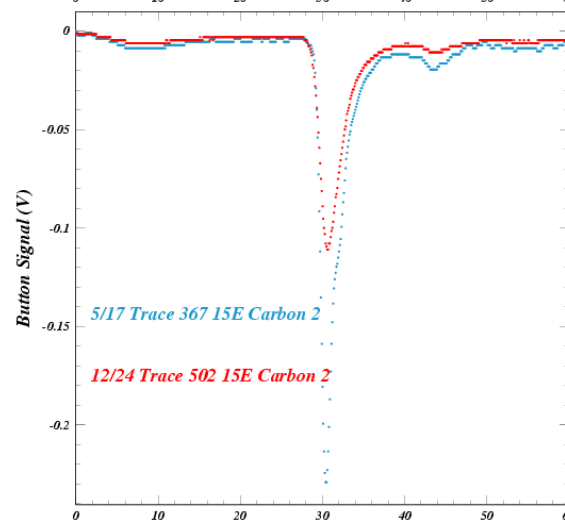
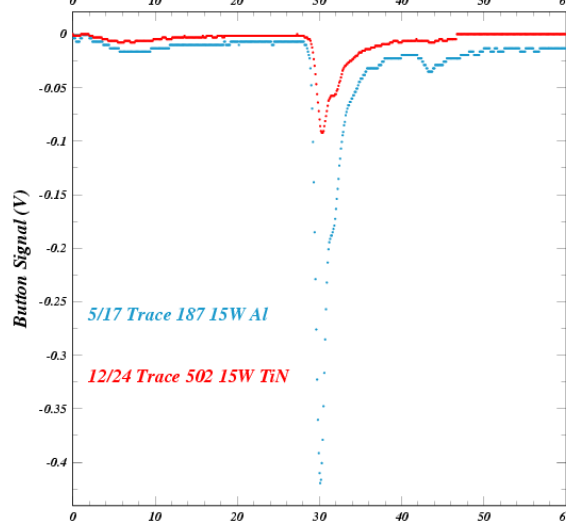
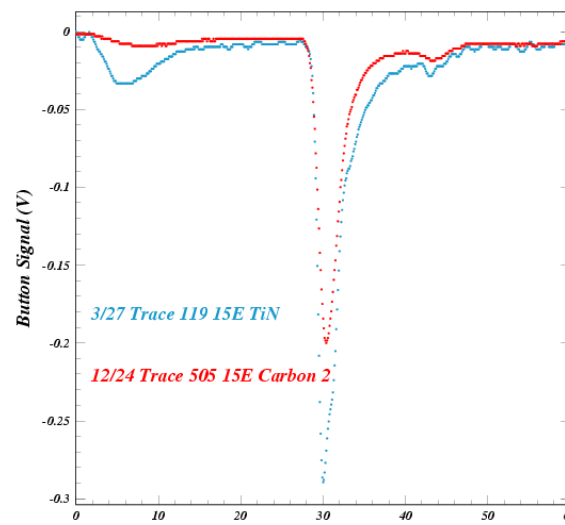
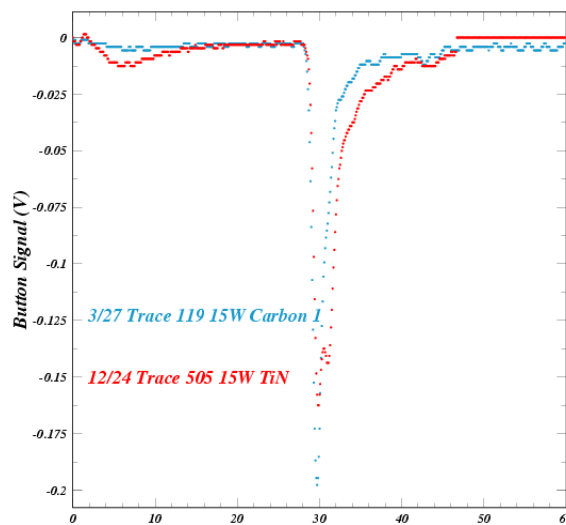


15W

15E

5 mA/bunch

3 mA/bunch



The carbon coating suppresses photoelectron production relative to the TiN coating, but the SEY may be higher.

Similar conclusions as for the first carbon-coated vacuum chamber.

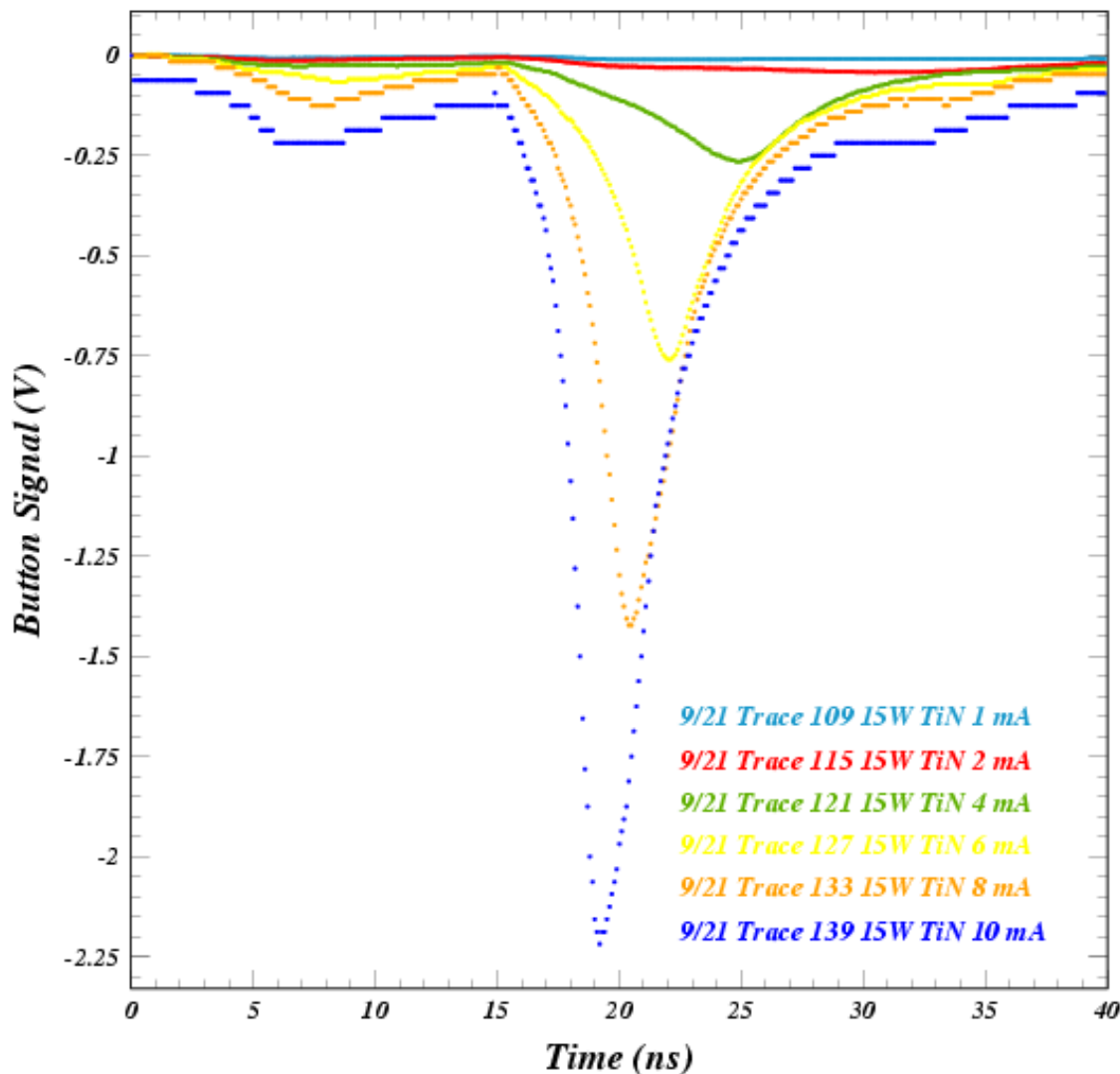
The measurements with the electron beam confirm the much smaller q.e. for reflected photons and SEY for TiN compared to Al found with the positron beam.

The electron beam measurements confirm the processing effect for the second carbon vacuum chamber observed with the positron beam.



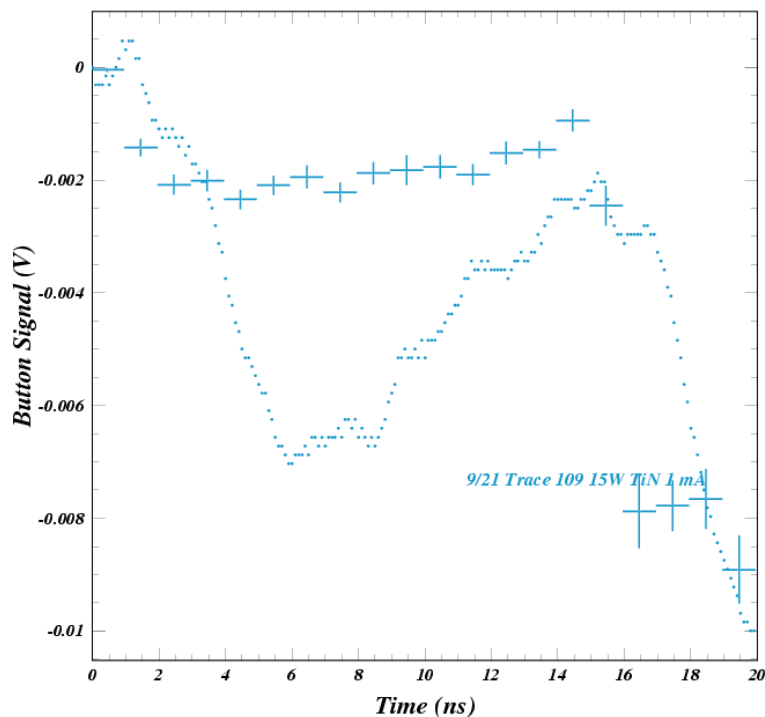
The bunch current scan of 9/21 confirms the nonlinearity in the TiN signal peak height observed in the vacuum chamber comparisons.

Remark from MAP: The AREAS of the signals are linear with bunch current at To better than 15%, as would be expected if primary photoelectrons dominated the signal, in which case the SEY curve will not affect it much. Simulations will tell.

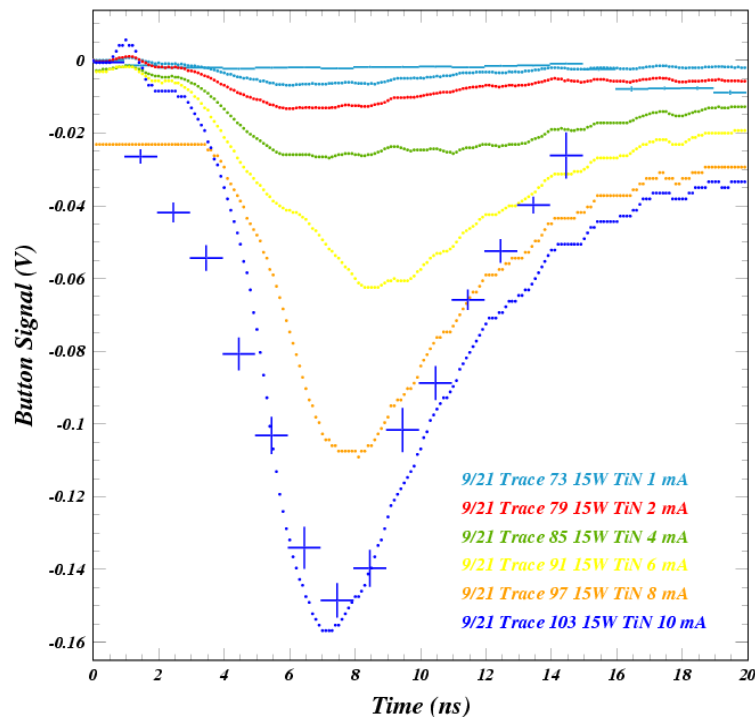




1 mA / bunch



1 -10 mA / bunch

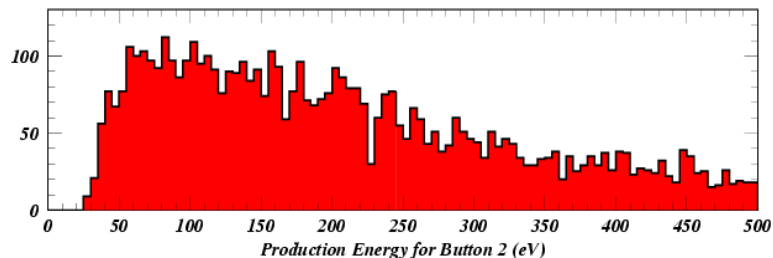
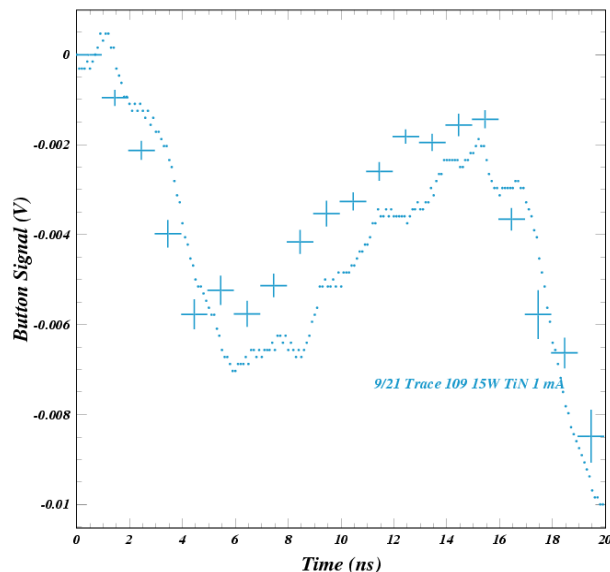


The bunch current scans provide a much more stringent test of the photoelectron energy distributions used in the simulation.

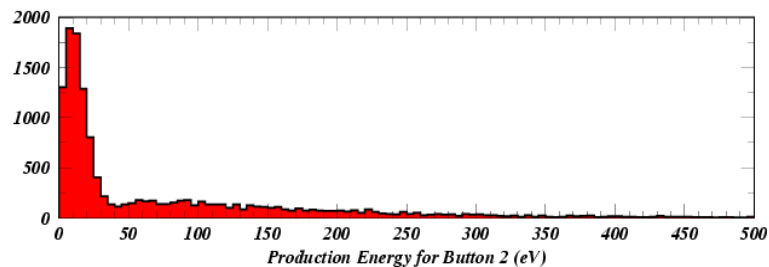
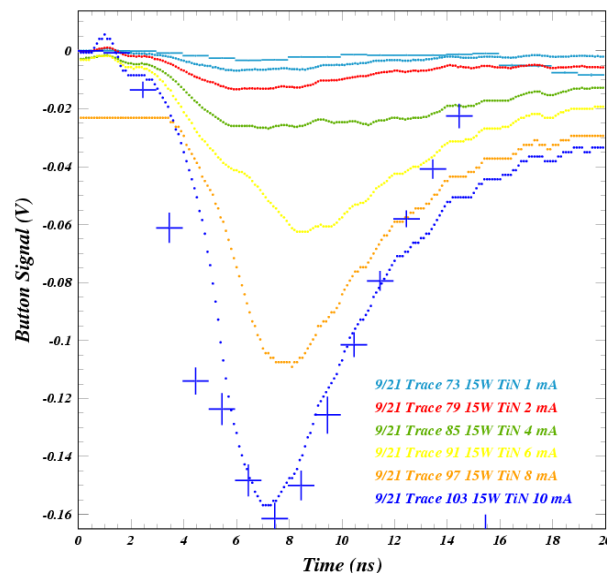
This example shows that the function used for the 3-mA witness bunch studies is a poor match for the 1-mA single-bunch signal, because the beam kick is not strong enough.



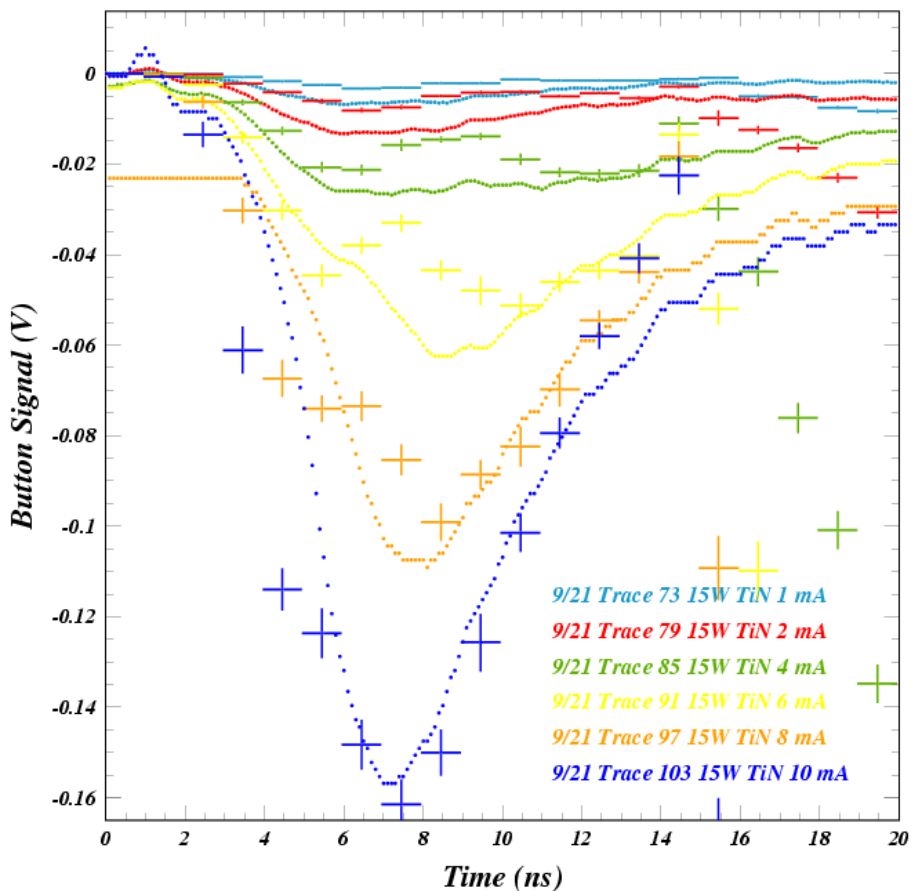
1 mA / bunch



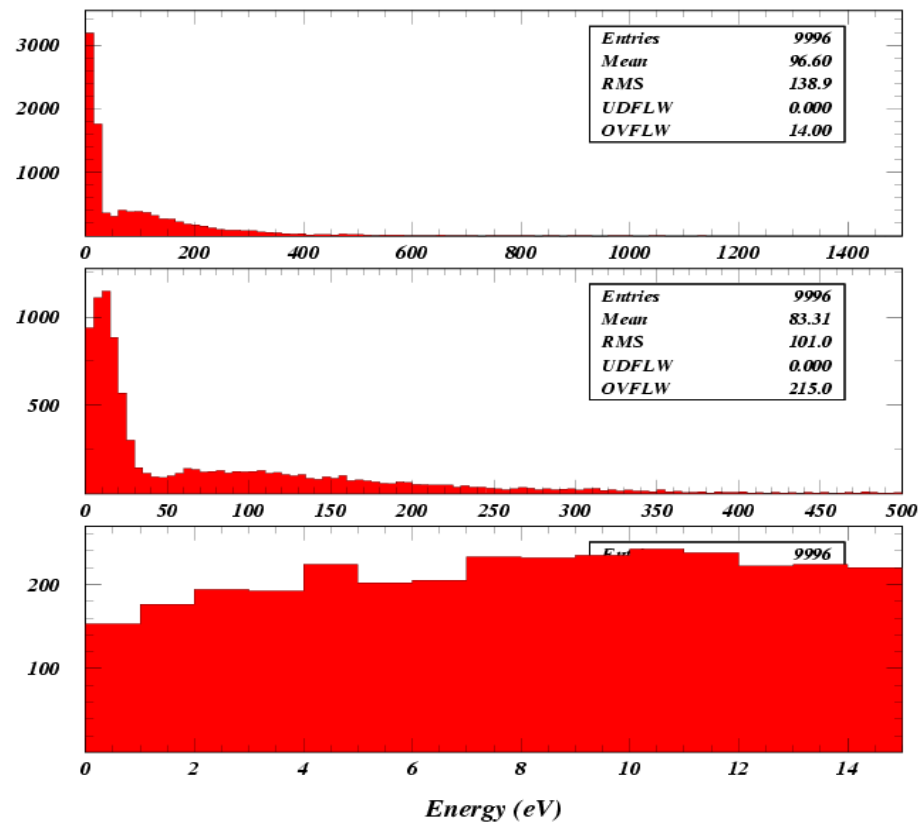
1 -10 mA / bunch



*After MUCH tuning work, the optimal p.e. energy distribution has changed a LOT.
These examples show why: the energy acceptance at 1 mA and 10 mA is very different.
The 10-mA signal requires a low energy peak to which the 1-mA signal is entirely insensitive.*



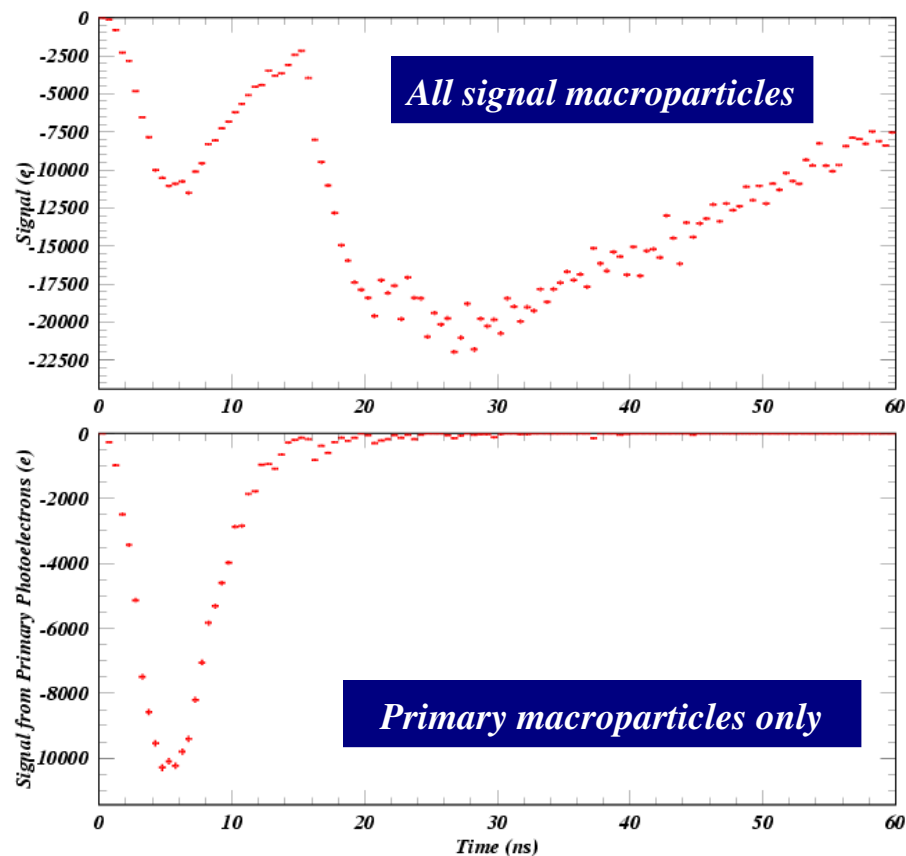
Job 20719: Primary Photoelectrons



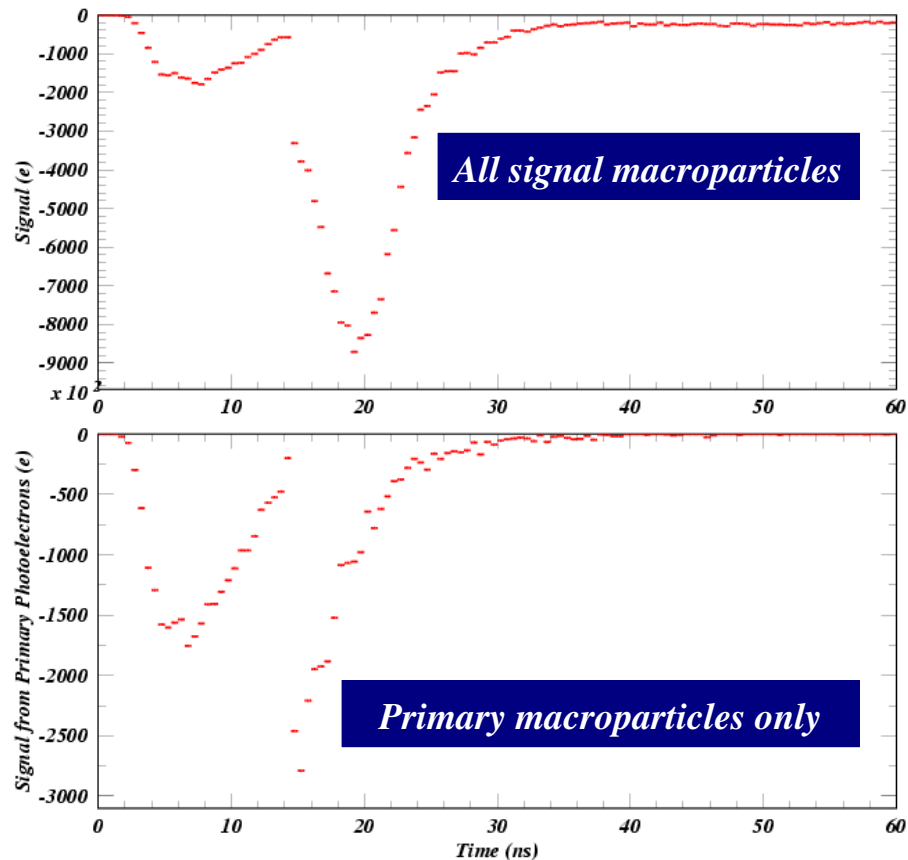
Still work to do. Dip is wrong.



1 mA / bunch



10 mA / bunch



Witness at 14 ns mostly secondaries for 1 and 10-mA bunch currents.